

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/529,790 | | Applicant(s)/Patent Under Reexamination SANO, TAKASHI | |
| | Examiner RuiMeng Hu | | Art Unit 2618 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-4,011,514 A | 03-1977 | Wroblewski, Jerzy | 455/169.2 |
| * | B | US-4,186,360 A | 01-1980 | Ohashi, Tadamasa | 334/55 |
| * | C | US-4,315,332 A | 02-1982 | Sakami et al. | 455/181.1 |
| * | D | US-5,117,206 A | 05-1992 | Imamura, Yoichi | 331/158 |
| * | E | US-5,136,719 A | 08-1992 | Gaskill et al. | 455/193.1 |
| * | F | US-5,670,881 A | 09-1997 | Arakawa et al. | 324/322 |
| * | G | US-6,172,576 B1 | 01-2001 | Endo et al. | 331/116R |
| * | H | US-6,181,218 B1 | 01-2001 | Clark et al. | 331/177R |
| * | I | US-6,239,675 B1 | 05-2001 | Flaxl, Thomas | 334/55 |
| * | J | US-2001/0036811 A1 | 11-2001 | Kianush et al. | 455/41 |
| * | K | US-6,686,804 B1 | 02-2004 | Adams et al. | 331/17 |
| * | L | US-2004/0214543 A1 | 10-2004 | Osone et al. | 455/197.2 |
| * | M | US-6,993,314 B2 | 01-2006 | Lim et al. | 455/333 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.